

<b>Notice of References Cited</b>	Application/Control No. 10/642,273	Applicant(s)/Patent Under Reexamination MAIER ET AL.	
	Examiner Richard L. Chiesa	Art Unit 1724	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,509,613	04-1985	Yamaguchi, Ken	180/219
	B	US-5,918,576	07-1999	Ohoka et al.	123/198E
	C	US-6,010,549	01-2000	Higashi et al.	55/385.3
	D	US-6,312,488	11-2001	Fischer, Christian	55/315
	E	US-6,391,073	05-2002	Koga, Hiroaki	55/289
	F	US-6,395,049	05-2002	Knodler et al.	55/385.3
	G	US-6,409,783	06-2002	Miyajima et al.	55/385.3
	H	US-6,454,823	09-2002	Fries et al.	55/385.3
	I	US-6,491,734	12-2002	Park, Kee-Youn	55/385.3
	J	US-6,578,831	06-2003	Menzel et al.	261/152
	K	US-6,607,574	08-2003	Maier et al.	55/385.7
	L	US-6,659,432	12-2003	Nickel, Hans	261/64.1
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.